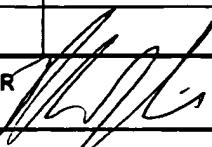


FORM PTO-1449		Docket Number (Optional) 294G 1787-2		Application Number 10/038,204		
INFORMATION DISCLOSURE CITATION IN AN APPLICATION		Applicant Colbert et al.				
(Use several sheets if necessary)		Filing Date 12/21/2001		Group Art Unit 1754		
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION (YES/NO)
PL	JP H06-331309	12/2/1994	Japan			YES
PL	JP H06-252056	9/9/1994	Japan			YES
PL	JP H07-122198	5/12/1995	Japan			YES
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
PL	"Imaging steep, high structures by scanning force microscopy with electron beam deposited tips" by David J. Keller, et al., pages 333-339 in the Surface Science magazine published by Elsevier Science Publishers B.V. in 1992 in Holland					
PL	"New Scanning tunneling microscopy tip for measuring surface topography" by Y. Akama, et al., pages 429-433 in Vac. Sci. Technol. A 8 published by American Vacuum Society in 1990					
PL	"Atomic force microscopy using ZnO whisker tip" by H. Kado, et al., pages 3330-3332 in Rev. Sci. Instrum 63 published by American Institute of Physics in 1992					
PL	"Helical microtubules of graphitic carbon" by Sumio Iijima, pages 56-58 in the Nature magazine Vo. 354 published in 1991					
PL	"Single-shell carbon nanotubes of 1-nm diameter" by Sumio Iijima et al., pages 603-605 in the Nature magazine Vo. 363 published in 1993					
PL	"Aligned Carbon Nanotube Arrays Formed by Cutting a Polymer Resin-Nanotube Composite" by P.M Ajaya, et al., pages 1212-1214 in the SCIENCE magazine Vo. 265 published in 1994					
PL	"Aligned Carbon Nanotube Films: Production and Optical and Electronic Properties" by Walt A. de Heer, et al., pages 845-847 in the SCIENCE magazine Vo. 268 published in 1995					
EXAMINER 		DATE CONSIDERED 1/24/05				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						